## 2IGHTMATTER

# Photonic-Enabled Heterogeneous Integration: The Future of AI System Scaling

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#### \$850M RAISED

Fidelity Google Ventures Sequoia Spark Capital Viking

T. Rowe Price Matrix Partners SIP Capital MIT Stanford

## OFFICES



Mountain View (HQ)



**Boston** 



## EMPLOYEΣS



Founder, CEO





Sujatha Wagle VP, Supply Chain Ops





Praveen Kukkamalla VP, Sales



Darius Bunandar, PhD Founder, Chief Scientist



Ritesh Jain SVP, Engineering & Ops



Beth Keil SVP, People



General Counsel



VP, Cloud Services Sales



Thomas Graham Founder



**Bob Turner** SVP. Sales & Solution Arch



Steve Klinger VP. Product



VP, Photonics & Si Eng



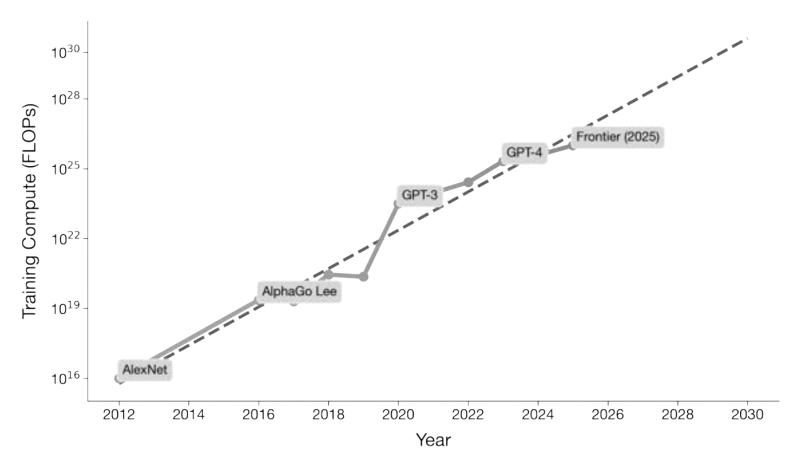
Head of Creative Marketing

## 311 PAZENTS

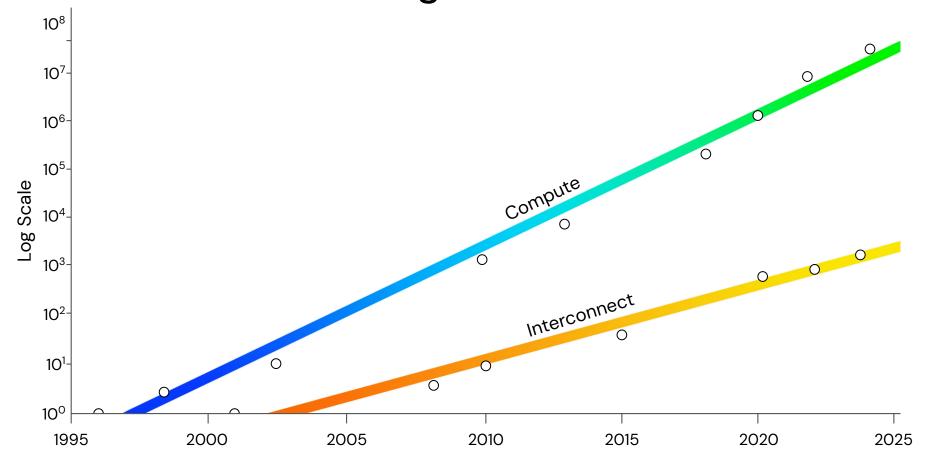


Granted & Pending

## 10<sup>9</sup> Growth in a Decade

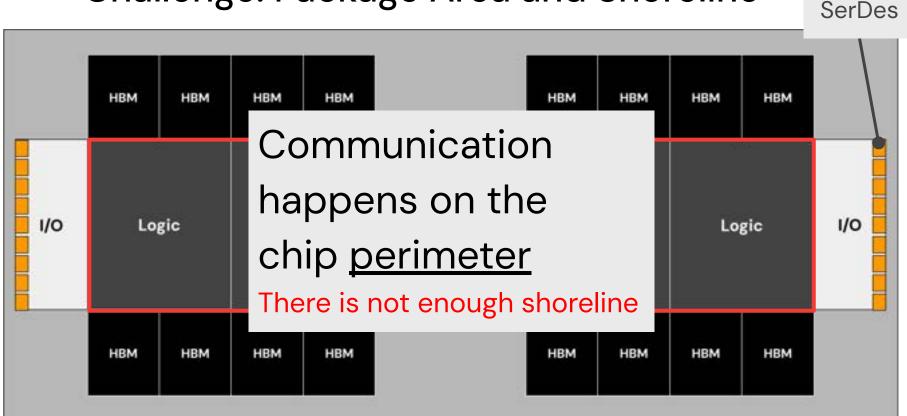


## Interconnect Progress Is Too Slow



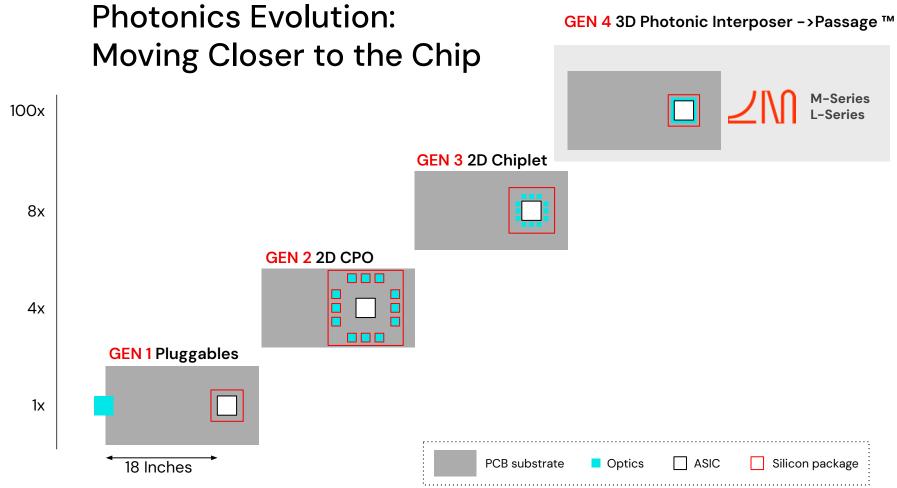


## Challenge: Package Area and Shoreline



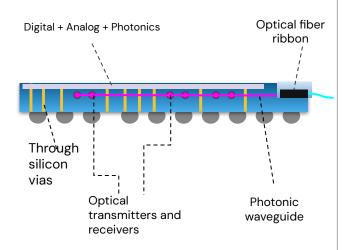
A new paradigm is needed

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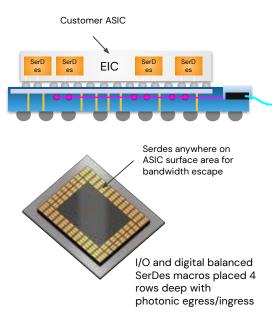
## Passage ™: 3D Photonic Interposer

#### **Photonic Integrated Circuit**

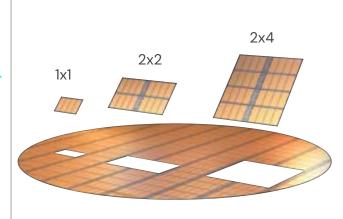


Passage Cross Section

(note: digital/analog can be integrated in top die; FAB choice dependent)



Passage value (3D integration) and density



optical waveguides stitched across reticle

Passage scalability from single to multi-reticle

Built on 3D packaging technology and a Chip-on-Wafer assembly flow

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#### 3D CPO Requires Compact Optical Modulators and Receivers

Standard Package Example

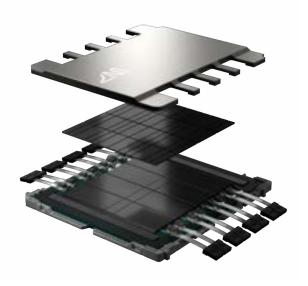
Fiber array unit & **EIC** Pluggable connector **Cross Section** IO Chip **UCle** Optical fiber ribbon XPU/Switch Chip UCle Photonic Integrated Circuit **Package Substrate** Power & Signals Photonic waveguide Optical transmitters Through silicon vias and receivers

#### Standard processes today

- Bump pitch: ~120 μm
- Bump size: ~80 μm
- Area for a transmitter/receiver: 0.015 mm²



### Passage M-Series

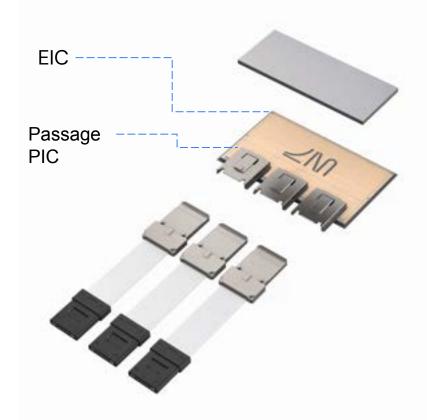


Photonic Interposer

Available Now

## Passage™ L-series 3D CPO

- Single reticle
- I/O EIC with UCle & SerDes
- >1.5 Tbps/mm bandwidth density
- Detachable FAU



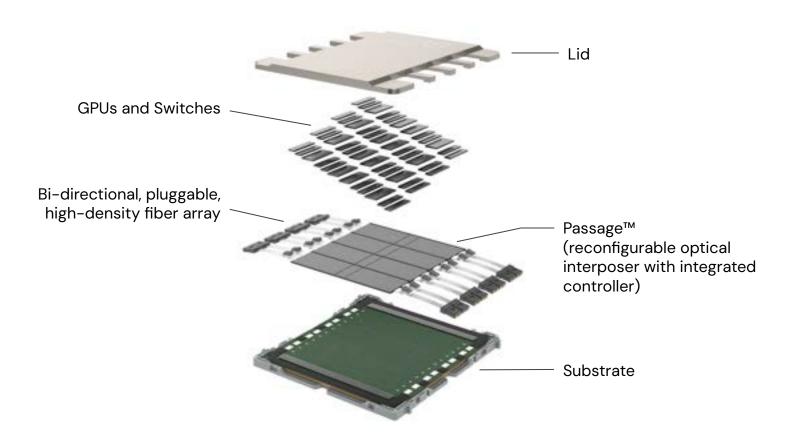
## 20 pluggables in the area of a quarter.



1.6 Tbps pluggables

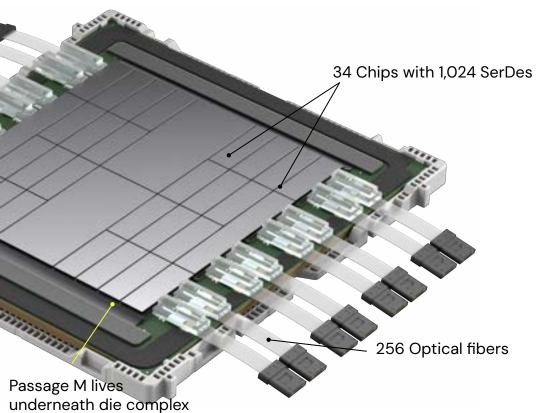
**L-Series** 

## Passage™ M Series: Multi-Reticle PIC



## Passage™ M Series

Photonic interposer reference platform

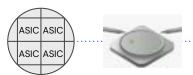


Specifications		
Bandwidth (Tx + Rx)	Up to 114 Tbps	
# of SerDes	1024	
Silicon die Complex	4,000 mm <sup>2</sup>	
Power delivery	>1.4 W/mm² density	
Fibers	256	
Redundancy	Optical circuit switching	
Substrate Form Factor	91x85mm	

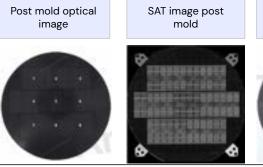
**Enables 114 Tbps total bandwidth.** 

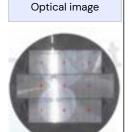
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#### M1000 How it's built.



ASIC





Post mold grind

PIC PIC

Wafer Test

TSV Reveal

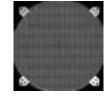
RDL and bumping

CoW reflow: PIC wafer (TSV) to ASIC attach

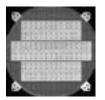
Wafer level underfill, mold and grind

Wafer dicing

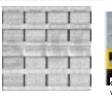








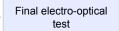




exposed optical

ASIC

System



Fiber attach with real time optical test

Package e-test (Known good PKG)



Post substrate attach reflow









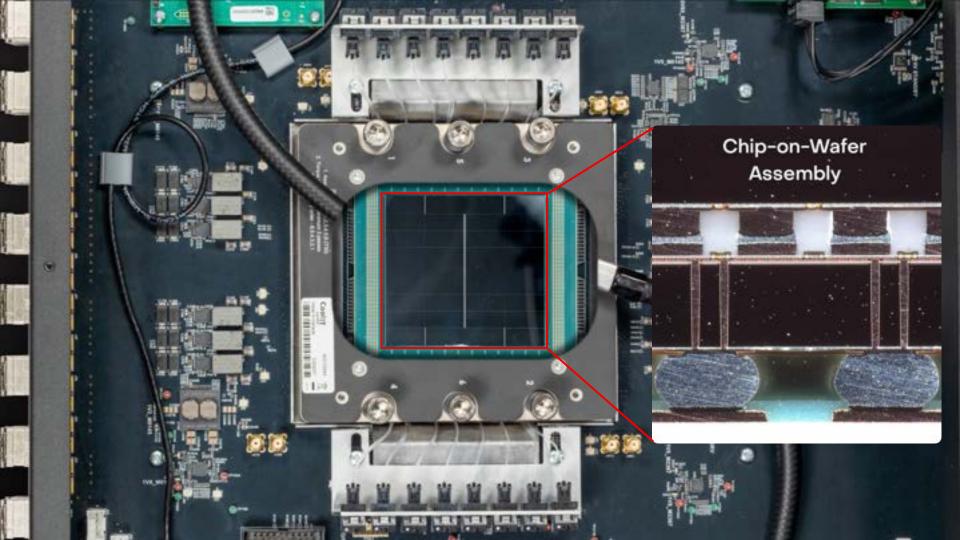






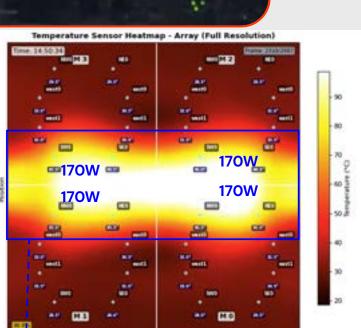






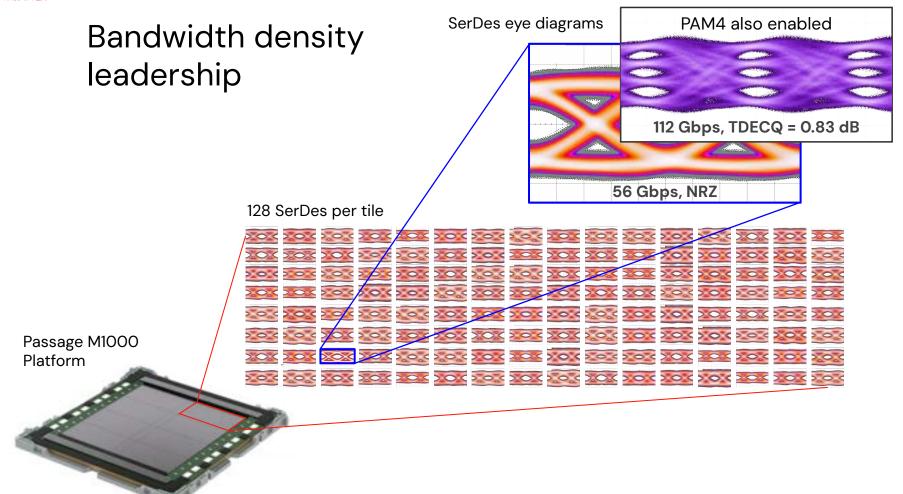
Power delivery and / thermal load





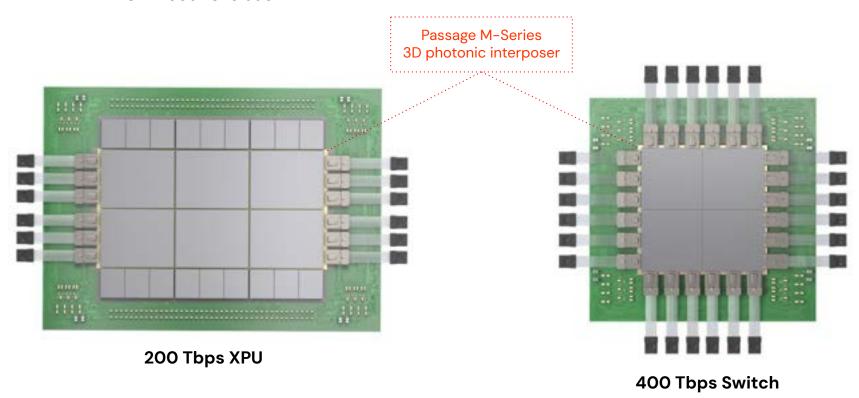
FLOW 1.8LPM LIQ TEMP 24.5C

369mm<sup>2</sup> thermal test chip, power density 1.47W/mm<sup>2</sup>. Passage TSVs support >2.5A/mm<sup>2</sup>.



## 3D Interposer scale-up and out to 1M nodes

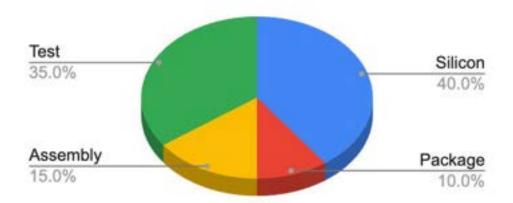
The M1000 revolution



### SPAT Costs and the Need for continued Innovation

Silicon, Package, Assembly, Test





Note: Graph shown for demonstration purposes only

For SiPho Relative Packaging, Assembly and Test (PAT) cost % is increasing

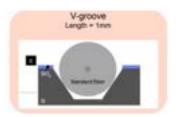
PAT cost challenges in SiPho:

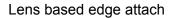
- In assembly: fiber attach yields
- 2. In test: test times are much higher

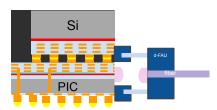
DFM/DFT-driven product architecture is must for high volume SiPho manufacturing and cost reduction

#### Fiber Attach Methods

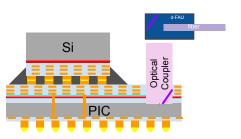
Traditional FAU







Wafer Level Optical coupler



V-Groove based Fiber Attach Methods	Lens based: Detachable fiber attach	LM Focus: Detachable fiber attach
Package level assembly (interface on die edge)	Package level assembly (interface on die edge)	Wafer level assembly and test compatible
Not compatible with 3D Arch	Compatible with 3D Package Arch	Compatible with 3D Package Arch
XPU to OE D2D: Standard Package	XPU to OE D2D: Standard & Adv. Package	XPU to OE D2D: Standard & Adv. Package
Passive or Active alignment	Active alignment	Passive or Active alignment
Test with FAU after package assembly	Test with FAU after package assembly	Test with FAU at wafer level
FAB: GF only	FAB: GF & TSMC	FAB: GF & TSMC
Serviceability: No	Serviceability: Yes	Serviceability: Yes
Limited scalability to HVM (\$\$\$)	Scalability to HVM (\$\$)	HVM scalable solution (\$)

LM driving strong ecosystem partnership to bring detachable FAUs to HVM scale



## Optimized end-to-end and production-ready

